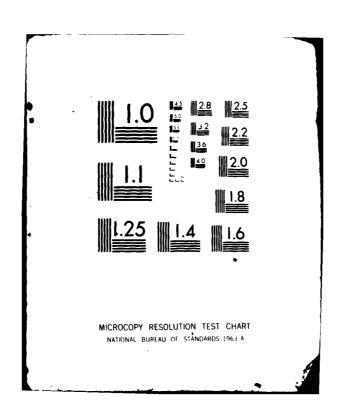
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Systems Research & Development Service Washington, D.C. 20590

# Modification of OE-258/URN Tactical Air Navigation (TACAN) Antenna Group

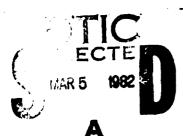
James D. Bain RANTEC DIVISION EMERSON ELECTRIC CO. 24003 Ventura Boulevard Calabasas, CA 9139

July 1981

Final Report

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# **PREFACE**

This final report describes the work done to modify the solid state OE-258/URN TACAN antenna group to remote monitoring of the Built-in-Test Equipment (BITE) including the following:

- Modification description
- Operation
- Installation of system
- Test results
- Conclusions and recommendations

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#### 1.0 INTRODUCTION

# 1.1 <u>Program Description</u>

This program, conducted in accordance with the requirements of Department of Transportation (DOT) Contract Number DTF01-80-C-10148, was designed to provide a modified Rantec Tactical Air Navigation (TACAN) Antenna Group (Model OE-258/URN) and provide field support during testing at Federal Aviation Authority (FAA) Technical Center at Atlantic City, New Jersey. The antenna modifications were in accordance with the contract Statement of Work. These modifications provide a computer interface between the TACAN Antenna Group and the Second Generation Very High Frequency Omnidirectional Radio Range/Tactical Air Navigation (VORTAC) System. The interface is in accordance with the Institute of Electrical and Electronics Engineers (IEEE) - 488 standards. In addition, a test set duplicating the control and display functions of the VORTAC System was provided.

The antenna group furnished for this contract was transferred to the FAA from the United States (U.S.) Navy. No changes were made to the antenna. The modulation generator, however, was extensively modified and has been furnished as an engineering prototype for test and evaluation.

# 1.2 Antenna Group Description

The OE-258/URN TACAN Antenna Group is an all-band, solid-state, electronically modulated antenna for use with Tactical Air Navigation (TACAN) systems. It is used with the TACAN ground transponder for both transmission and reception, and provides the horizontally rotating 9-lobed pattern for the TACAN azimuth modulation characteristic. The use of electronic modulation deletes the requirement for any moving parts within the antenna, thus improving reliability and reducing power consumption. The Antenna Group consists of two major units, the Antenna and the Modulation Generator. This antenna is used in conjunction with a TACAN radio set (ground transponder) to provide a navigational signal for aircraft (distance and bearing for military users and distance for all users of the National Airspace). Figure 1-1 depicts this equipment relationship. Aircraft equipped with a companion TACAN interrogator unit derive slantrange distance to the ground beacon and bearing angle, referenced to majnetic north.

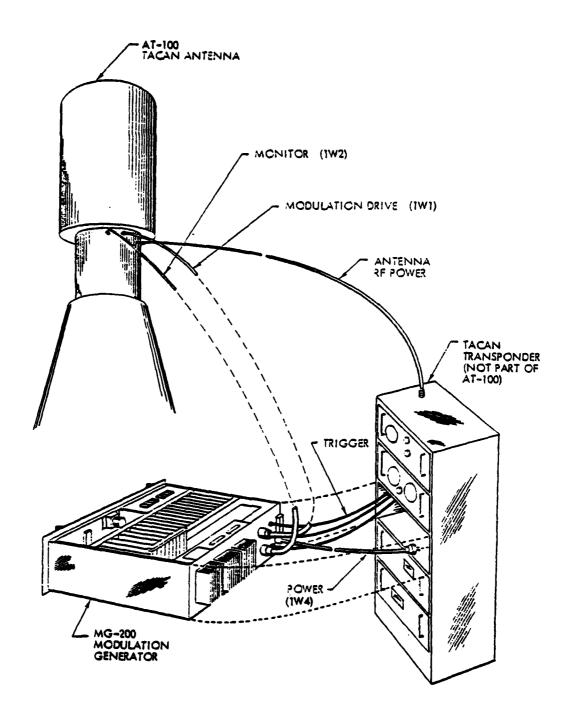


Figure 1-1. AT-100 TACAN Antenna Group, Relationship of Units

- a. Antenna. The antenna unit is a cylindrical array approximately 84 inches high and 60 inches in diameter. It consists of 36 identical and equally spaced vertical radiating columns, providing for the transmission and reception of the pulse-paired rf signals. One antenna element is shown in Figure 1-2. The use of the cylindrical array configuration for the TACAN antenna presents several advantages:
  - (1) The use of cavity feed slots within the vertical arrays provides a very pure vertically polarized signal from the antenna, thus eliminating cross-polarization problems.
  - (2) Since the carrier, 15 Hz and 135 Hz modulation components are all radiated from the slots, they have the same basic radiation characteristics. Low-level signals below the horizon are maintained for all radiation components, thus minimizing ground reflection problems.
  - (3) Careful matching of the radiators and other rf components, together with the basic array geometry, permits single antenna operations over the entire TACAN band.

The cylindrical antenna base houses the modulators, power splitters, and associated circuitry and increases the overall height to 124 inches, with a total weight of approximately 850 pounds. Figure 1-3 shows the complete antenna with its environmentally protecting radome. Figure 1-4 diagrams the internal arrangement of the rf feed structure. In this figure:

Al thru A36 are the vertical radiators.

A37 thru A39 are the azimuth feeds (12-way power dividers and PIN diode modulations).

A40 is the input, 3-way power divider.

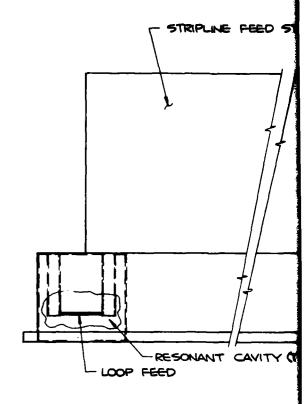
A40A1 is the antenna-monitor printed circuit card.

J3/W40 provides the antenna rf input path.

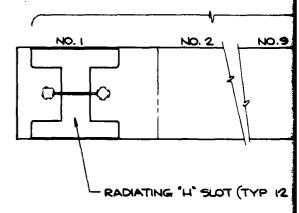
J2/W42 provides the modulation drive input from the modulation generator.

J3/W41 provides the antenna monitor connections to the modulation generator from 1A40A1.



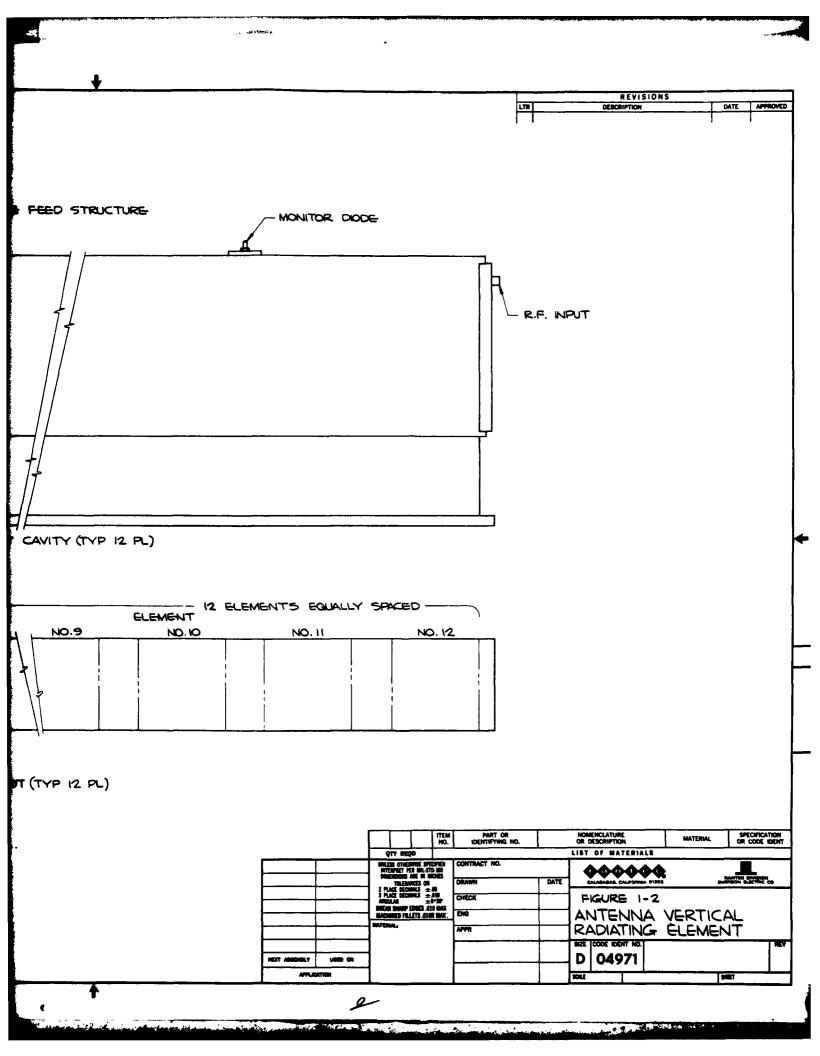


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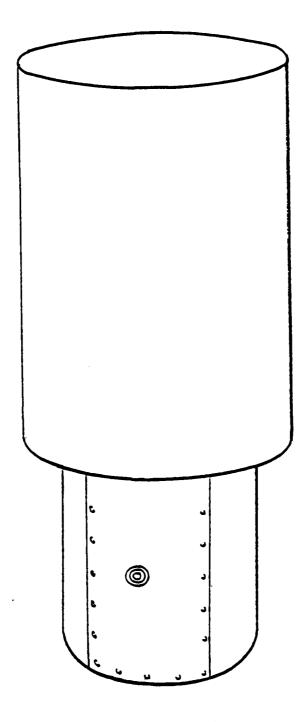
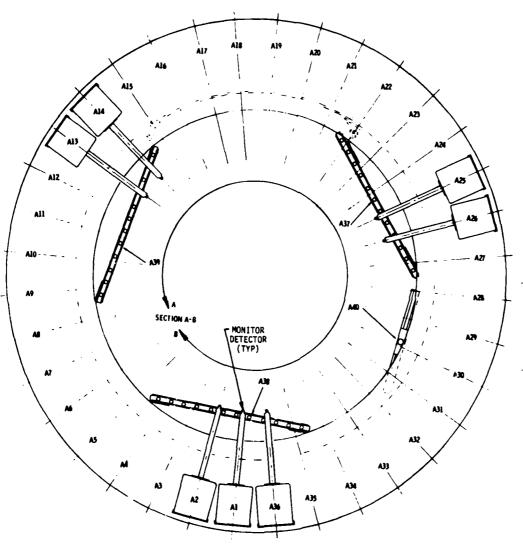


Figure 1-3. TACAN Antenna



CONNECTOR OF VERTICAL FEED NO. (REF)

·····/

TOP CUT-AWAY VIEW

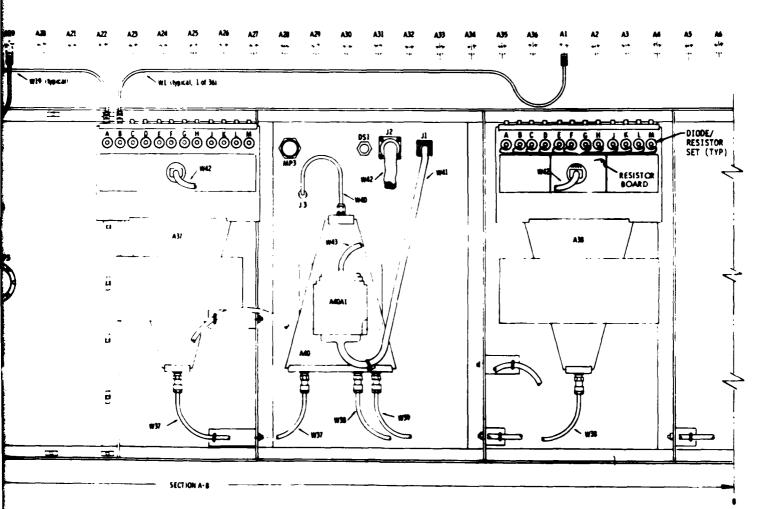


Figure 1-4. TACAN Antenna - RF Feed Structure

W43 provides signals from the 36 monitor diodes on each vertical divider (A1 through A36) to 1A40A1.

Other rf cables are self explanatory.

b. <u>Modulation Generator</u>. The modulation generator provides the 36 drive signals for PIN diode modulators in the antenna, which in turn produce the TACAN system's horizontally rotating pattern in space.

This unit also provides bipolar signals to the beacon transponder for timing the transmission of north and auxiliary reference bursts. A bipolar 1350 Hz signal is also supplied for the generation of a Morse-code station identification signal. Built-in-test equipment (BITE) circuits are provided to continuously monitor antenna group performance. The modulation generator is configured for mounting in a standard 19 inch wide rack, and has a front panel height of 8.75 inches, as shown in Figure 1-5. The unit is supplied in a self-contained cabinet with drawer slides.

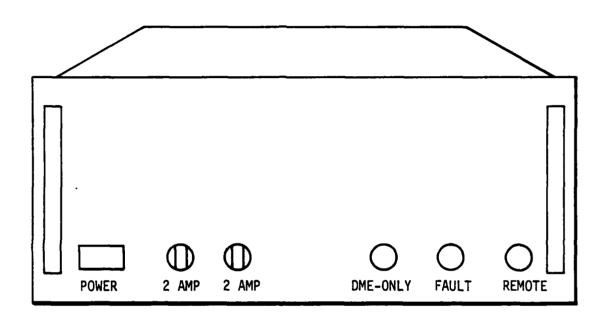


Figure 1-5. Modulation Generator

#### 2.0 ANTENNA GROUP MODIFICATIONS

# 2.1 General

Modification of the TACAN Antenna Group was concerned only with the built-in test equipment (BITE) functions of the modulation generator and its interconnections to the computer interface. Thus no change was required in the antenna assembly or to the basic modulation drive and trigger signals from the modulation generator.

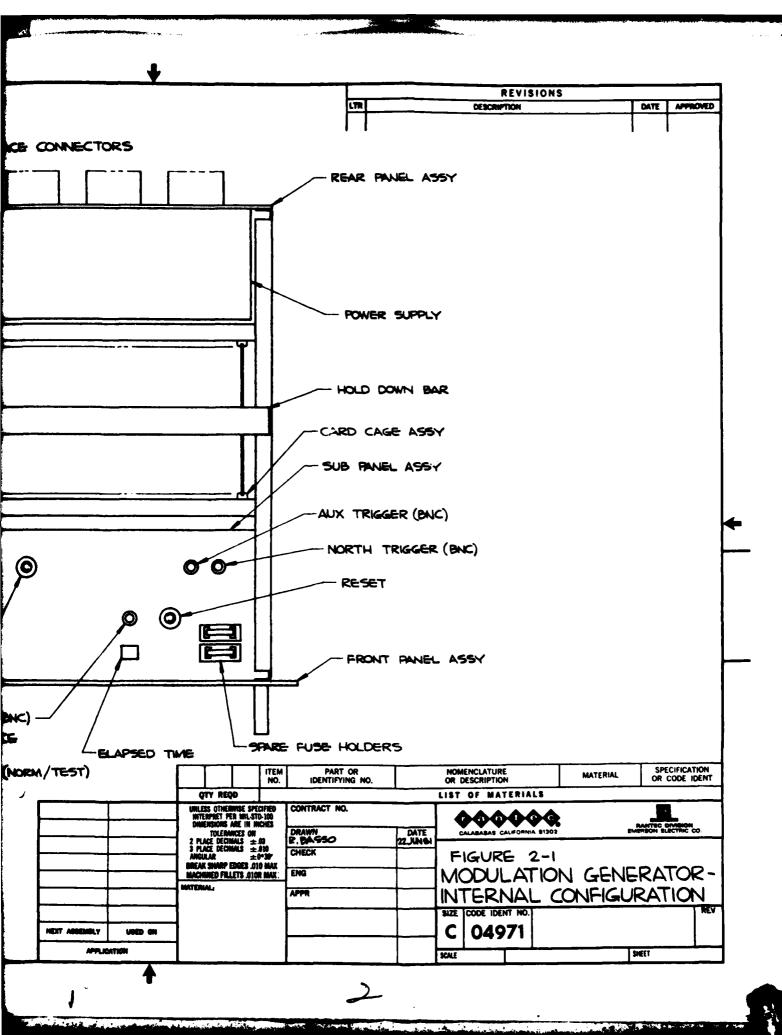
Physically the modulation generator front panel was modified such that it contains only a power switch, fuses, and FAULT, DME ONLY, and AUTO OPR lamp indicators. The rear panel was modified to contain the required interface connector. The interior was rearranged so that the internal panel contains certain of the operating and test switches formerly mounted on the front panel as shown in Figure 2-1.

The function of the various controls is listed below:

- Test sample select switch Selects various critical wave forms for output on the test sample connector.
- Test sample connector Outputs critical wave forms for display on oscilloscope.
- Operation switch In 'Normal' the BITE system is scanning all 36 channels of modulation drive and antenna monitor signals. In 'TEST' the BITE system count is stopped and may be advanced one channel at a time using the -
- Advance switch
- Sync connector outputs a TTL pulse synchronous with the start of each BITE channel count.
- Aux trigger outputs a TTL pulse synchronous with the center of the bipolar auxiliary reference signal.
- Nor trigger outputs a TTL pulse synchronous with the center of the bipolar north reference signal.
- Elapsed time displays modulation generator operating time in hours.

 North align thumbwheel - permits alignment of the antenna to magnetic north.

INTERFACE CONNECTORS TEST SAMPLE SELECT -TEST SAMPLE (BNC) SYNC(BNC) -ADVANCE ELAPSED TIME -OPERATION (NORM/TEST) QTY REQD NORTH ALIGN THUMBWHEEL HEXT ADDEMOLY -



Circuit design for the required modifications required the replacement of six printed circuit cards (PCC's) and the addition of one PCC.

The replaced PC cards eliminate the circuitry required for (BITE) indicator lamps and beacon-shut-down circuitry which were a part of the original modulation generator. Added circuitry allows these BITE signals to be applied to the IEEE-488 bus. In addition the BITE circuitry for the trigger and antenna monitor signals were improved. The bipolar trigger signals are now monitored for both their positive and negative going voltage levels. The antenna monitor was changed to permit detection of both over and under modulation conditions and a column-radiated home level monitor was added. Finally, a monitor-diode bias monitor was added.

The additional PC card was required for implementation of the IEEE-488 interface circuitry. The total BITE/interface system is discussed in paragraph 2.2 and shown in Figure 2-2.

In accordance with the contract this modified modulation generator was furnished as an engineering prototype.

# 2.2 BITE System Concept

The BITE concept for the solid state antennas requires a different criteria than that required for a mechanically rotating antenna. The required parameters are discussed below together with their relationship to the solid state design.

#### 2.2.1 Modulation Frequency

The modulation frequency is determined by crystal oscillators running at 3.456 MHz. Two identical oscillators are used and their frequency is compared to  $\pm 0.35\%$ . Thus the modulation and trigger frequency is accurately controlled. There can be no "WOW" or other perturbation to this basic frequency.

#### 2.2.2 Trigger Signals

Since the trigger signals are generated electronically their basic frequency is assured. However, the BITE system is required to assure that the bipolar signals are present and that they occur in correct relationship and number.

#### 2.2.3 Antenna Monitor

Since the solid-state antenna is an array, its' far-field pattern is a summation of the carrier and modulation from several of its 36 vertical columns. The accuracy of the bearing information is related within each column to:

- Phase of modulation signal
- Amplitude of modulation
- Phase of rf signal
- Amplitude of rf signal

The phase and amplitude of the modulation signal is controlled to a major extent by the 36 drive signals from the modulation generator. The BITE system uses a secondarily generated drive signal as a comparison in a summing network. The resultant 'generator-null' signal will detect errors of greater than 2 degrees or 0.6 dB in phase and amplitude. Only one column drive being outside these limits will have only a minor impact on antenna performance (see Appendix A).

The phase of the rf signal is determined by the rf path length through the antenna circuitry. This parameter is carefully controlled during antenna manufacture and is unlikely to change to any marked extent.

The rf paths themselves are either low-loss coaxial cable or stripline. The only active components are the PIN diode modulators, the monitor diodes and the circuitry on the antenna monitor PCC (A40A1). Failure is, of course, more likely to occur in these active components. Present in-service antennas, however, indicate that these units are extremely reliable.

A monitor diode is connected to each of the 36 vertical arrays in the antenna. As processed in the modulation generator, these monitor signals will indicate both degradation of the rf signal level and degradation in the modulation signal. Here again the loss of one column does not seriously impact antenna performance.

The monitor diodes themselves are also checked (for bias level) to insure that failure of this element does not cause system false alarms.

# 2.3 BITE System Operation

The characteristics of the modified BITE system is described in the following paragraphs. Any detected fault will cause a system interrupt so that appropriate system analysis and a BEACON SHUT DOWN or DME ONLY decision can be made. A simplified block diagram of the BITE and interface circuit is shown in Figure 2-2. Complete data concerning the operation of this circuitry is contained in the Technical Manual Addendum (Rantec No. 11016-ATM) furnished with the modified antenna group.

# 2.3.1 Trigger Faults

The bipolar north, auxiliary, and tone signals are measured for the amplitude and presence of both the positive and negative going portion of their respective waveforms. These signals are also checked for the correct number of pulses as a function of time:

North - One and only one pulse between consecutive Auxiliary groups.

Auxiliary - Eight and only eight pulses between consecutive North pulses.

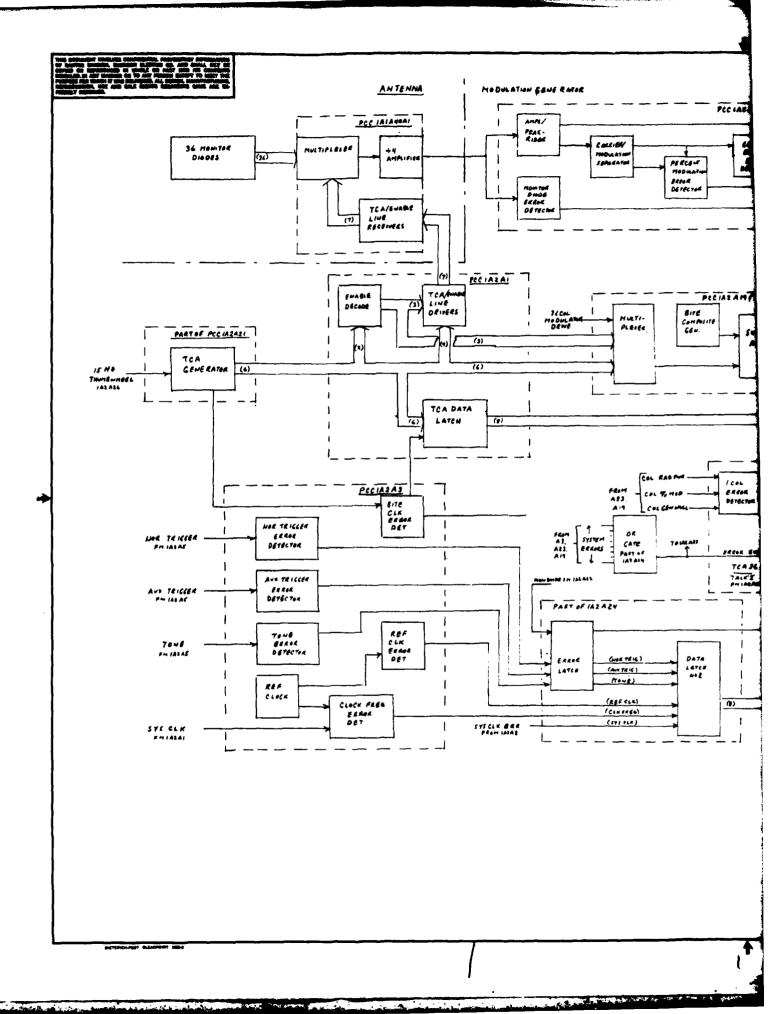
Tone - Ten and only ten pulses between the north pulse and the second auxiliary pulse.

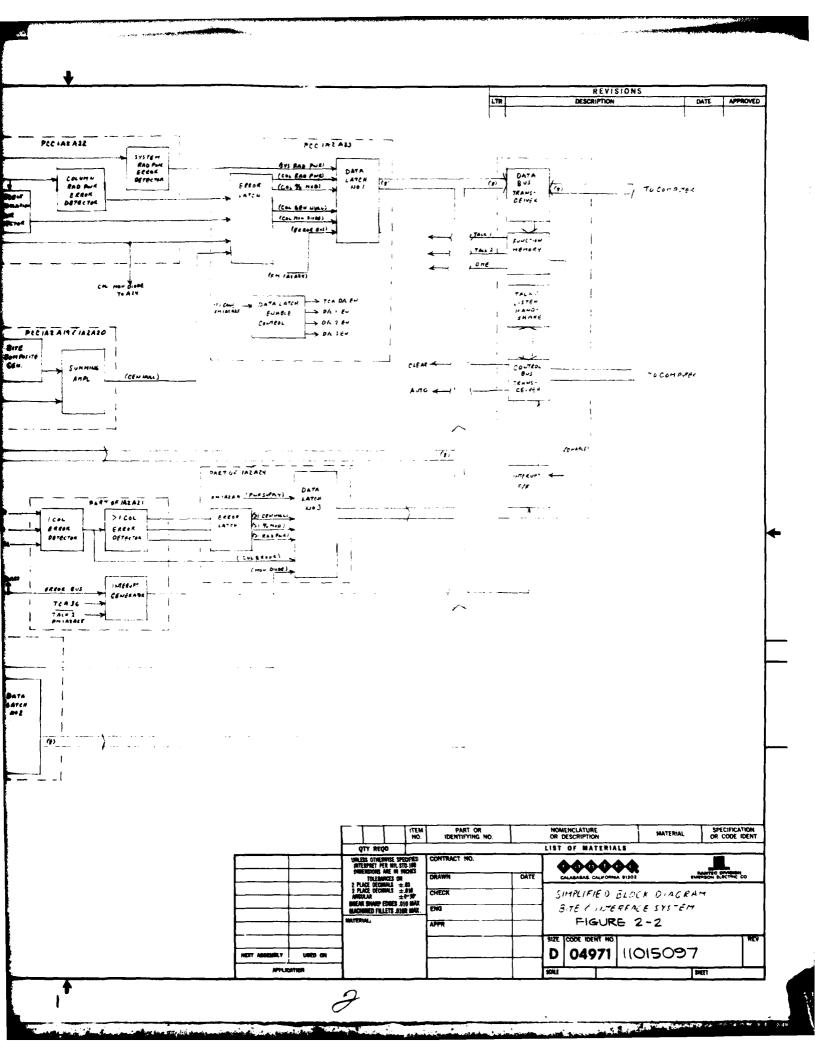
Failure of the North or Auxiliary pulses is decoded in the test set as a hard error. Failure of the Tone signal is decoded as a soft failure.

#### 2.3.2 Clock Faults

The presence of the system and reference clock signals is detected and are decoded as soft failures. These two signals are compared to test the clock frequency. Failure of this parameter is decoded as a hard failure.

Note: The failure of either clock disables the clock frequency test. Prompt repair action is therefore dictated.





# 2.3.3 Power Supply

The + and - 16 volt power supply output is monitored for a five percent deviation from nominal. A greater deviation is detected and decoded as a soft error.

#### 2.3.4 Monitor Diode

The 36 monitor diodes for detecting the radiated signal characteristics of the 36 antenna columns are biased to achieve the required linearity and sensitivity. If a diode becomes open or shorted this bias voltage will change. This bias voltage level is detected by a comparator which will detect a fault for voltages outside preset limits. This fault is decoded as a soft failure.

In the test set, this parameter is detected on a column-by-column basis during a complete status scan. A diode fault in any column disables the antenna column radiated power and column percent modulation tests for that column. This will prevent false hard failures of the >1 column error parameters.

#### 2.3.5 Generator Null

The drive signals to the 36 antenna column PIN-diode modulators are tested for phase and amplitude using a separately generated waveform. This test checks amplitude to within  $\pm 0.6$  dB and phase to within  $\pm 2$  degrees. A detected fault is decoded initially as a soft error. Should more than one column indicate a fault then a >1-column generator-null hard error is detected and decoded.

#### 2.3.6 Antenna Parameters

The output of the 36 monitor diodes are utilized to detect column radiated power and column percent modulation faults. The column radiated power is initially detected and decoded as a soft failure for signal levels 3 dB below the preset level. Percent modulation is initially detected and

decoded as a soft failure for levels less than 20 percent and greater than 60 percent for the composite 15 and 135 Hz modulation components. More-than-one-column faults are detected and decoded as appropriate >1 column hard errors.

#### 2.3.7 System Radiated Power

The average carrier level for all 36 antenna columns is detected and decoded as a soft failure for levels 6 dB below the preset level. This fault disables the column radiated power and column percent modulation tests to prevent hard failures when the beacon is off.

# 2.3.8 BITE Clock

A 3.75 Hz clock is used to drive the 36 channel sequential fault detection system. The presence of the test channel address '1' bit is detected and its absence is decoded as a hard failure.

# 2.4 Computer Interface

#### 2.4.1 General

The computer interface uses the IEEE-488 bus. Since only one interrupt (SRQ) line is present, then all antenna faults must result in interrupts and the BEACON SHUTDOWN analysis must be handled by the system computer and/or operator. The data transfer and interrupt operation are described in the following paragraphs.

#### 2.4.2 Data Lines

The interface provides a parallel 8-bit data bus. The modulation generator therefore requires four 8-bit latches to handle the required data. At each test channel address these latches are clocked and will contain all of the antenna status information for that test address.

# 2.4.3 Data Transfer

The modulation generator is designed as a "TALKER" using two different secondary addresses. When placed in the TALK mode the contents of each of the four data latches is read in turn, their enable circuits being controlled and counted by the data transfer "hand-shake" process.

#### 3.0 TEST SET

# 3.1 General

The test set provided with the TACAN antenna group is a Tektronix 4051 Graphics Computer which utilizes the IEEE-488 bus for interfacing with external periferal equipment. This unit has been programmed to provide operational and system test data similar to that which would be implemented in the Second Generation VORTAC System. The operation of the various monitor and test modes of this unit are described in the following paragraphs.

# 3.2 Executive Mode

Following initial system turn-on, the computer is placed in the executive mode by depressing USER DEFINABLE KEY '1'. In this mode the computer is in a loop which awaits a system interrupt. Such an interrupt is generated whenever a system fault is detected. When in this mode, the modulation generator AUTO lamp will be on and the computer display will be as shown in Figure 3-1. When a fault is detected the display changes to that shown in Figure 3-2 and appropriate errors will be indicated. For a column associated error the display will include an '+' under the test channel address (TCA) of the first column error and the COLUMN ERROR entry will be preceded by an 'X'. When the fault is not column related, the '+' will appear under non-column (NC) and the appropriate error will be indicated by a preceding 'X'. No individual column-related errors are displayed for this mode - a STATUS TEST must be performed to display these data.

Following this fault indication, the computer program stops and the operator is given the choice of various options to continue. It should be noted that the TACAN Antenna Group interrupt is disabled at this time and is reset only when the EXECUTIVE routine is restarted by depressing USER DE-FINABLE KEY '1'. This is accomplished automatically following a data print-out (see paragraph 3.6).

EXECUTIVE, SRQ ENABLED

TO RUN TESTS, U/D KEY:

- '2' STATUS TEST
- '3' BITE TEST
- '4' DME ONLY

Figure 3-1. Display for Executive Mode

# ---TACAN ANTENNA STATUS---

COL ERRS	00000000011111111111222222 1234567890123456789012345					
TEST COL ADDR	<del>+++++++++++++++++++++++++++++++++++++</del>					
HARD ERRORS	SO	FT ERRORS				
->1 GEN		-SYS CLK				
->1 RAD ->1 PERC		-REF CLK -TONE				
- CLK FR - NOR TR		-MON DIODE -COL ERROR				
- AUX TR		-PWR SUP -SYS RAD PWR				

# SRQ DISABLED

# TO CONTINUE, U/D KEY:

- '1' EXECUTIVE
  '2' STATUS TEST
  '3' BITE TEST
  '4' DME ONLY
  '5' PRINT DATA

Figure 3-2. Test Set - Data Matrix Display

# 3.3 Status Test Mode

The Status Test Mode is entered by depressing USER DEFINABLE KEY '2'. This mode may be entered following an interrupt to ascertain the complete status of the TACAN antenna group. It may also be entered directly from the Executive mode to verify that the TACAN antenna group operation is normal. This mode causes the computer display to be as shown in Figure 3-2. The test-channel address scan rate then changes from 267 msec to 1 second per channel. In the absence of an error, an '+' will be sequentially displayed beneath each TCA address and then "TACAN ANT OPERATION NORMAL" will be displayed. For errors, the various column-related errors will be displayed beneath the appropriate TCA number. Hard and soft errors will be displayed following the TCA 36 count. Whenever this test is run, the TACAN antenna interrupt is disabled. A return to the Executive mode is required to reset the interrupt enable condition.

# 3.4 Bite Test Mode

The Bite Test Mode is entered by depressing USER DEFINABLE KEY '3'. This mode causes the various error latches in the modulation generator to be preset to the error condition. The computer will display Figure 3-2 and all of the fault indications except SYS RAD PWR and PWR SUP will show an 'X'. The TCA will indicate one arbitrary column and the column errors beneath it will show 'X's. the TACAN antenna interrupt is also disabled for this test. This test does not affect the normal operation of the antenna and may be performed at any time.

# 3.5 <u>DME-Only Mode</u>

The DME-Only Mode disables one of the primary oscillator-divider signals such that the bipolar triggers are turned off and the modulation drive is stopped at some arbitrary position. This operating mode is intended for use when a modulation generator, beacon, or antenna fault precludes operation in the normal TACAN mode. The TACAN antenna interrupt is disabled. Reset to normal is accomplished by returning to the Executive Mode. This

operating mode causes the TCA data-latch 128 bit to be high. This bit is stored and decoded by the DATA PRINT operation (paragraph 3.6) to print out "DME ONLY mode".

# 3.6 Data-Print Mode

Whenever data is received by the computer bus due to an interrupt or a status scan, this data is available for transmission over a remote TTY line. Various printouts will occur depending upon the status (see Figure 3-3). This routine uses additional programming on the computer tape and uses the RS-232 serial output port. Upon completion of a data printout, the system will automatically return to the Executive mode.

A bite clock failure causes the TCA data latch 64 bit to be high. This bit is stored and decoded by the Data Print computer program to print out "BITE CLOCK FAILURE".

# 3.7 Error Decoding

#### 3.7.1 General

Four tri-state eight-bit latches contain antenna TCA and status data. For each TCA the content of these latches is updated and is available for transmission over the computer 8-bit parallel data bus. The variable E is assigned by the computer software to read and store these bytes, using array sizes appropriate to the selected test mode. In the computer software, the variables A, B, C, and D are assigned the values of the four bytes. A will be equal to the current TCA and can be read directly. BITE CLK errors and DME ONLY status is also contained on this latch (see paragraph 3.4). The variables B, C and D are decoded by routines which ascertain which of the individual bits are high (no error) or low. These routines result in the display of 'X's for those bits which indicate errors. Table 3-1 contains the menu for the contents of the four bytes.

# EXAMPLE 1.

----TACAN ANTENNA STATUS----OPERATION NORMAL ----END OF DATA----

# EXAMPLE 2.

----TACAN ANTENNA STATUS----TCA GEN RAD PERC MON NULL PWR MOD DIODE 3 X X 7 X X ----HARD ERRORS

>1 COL RAD PWR

>1 COL PERC MOD

----SOFT ERRORS

COL ERROR

----END OF DATA----

# EXAMPLE 3.

----TACAN ANTENNA STATUS----DME ONLY MODE ---END OF DATA----

Figure 3-3 Data Printout Examples

TABLE 3-1
DATA LATCH MENU

D/L No	Bit No	Decima1	Function	Reset
TCA	1	1	TCA1 (Binary)	Each TCA
(1A2A1)	2	2	TCA2 (Binary)	Each TCA
	3	4	TCA4 (Binary)	Each TCA
	4	8	TCA8 (Binary)	Each TCA
	5	16	TCA16 (Binary)	Each TCA
	6	32	TCA32 (Binary)	Each TCA
	7	64	BITE CLK ERROR (HI on error)	N/A
	8	128	DME ONLY (HI on DME only)	N/A
1	1	1	ERROR BUS (HI on error)	N/A
(1A2A23)	2	2	COL MON DIODE (LO on error)	Each TCA
	3	4	SYS RAD PWR (LO on error)	N/A
	4	8	COL RAD PWR (LO on error)	Each TCA
	5	16	COL PERC MOD (LO on error)	Each TCA
	6	32	COL GEN NULL (LO on error)	Each TCA
	7	64	-Always HI-	N/A
	8	128	-Always HI-	N/A
2	1	1	REF CLK (LO on error)	TCA36/TCA1
(1A2A24)	2	2	CLK FREQ (LO on error)	TCA36/TCA1
	3	4	NORTH (LO on error)	TCA36/TCA1
	4	8	AUX (LO on error)	TCA36/TCA1
	5	16	TONE (LO on error)	TCA36/TCA1
	6	32	SYS CLK (LO on error)	TCA36/TCA1
	7	64	-Always HI-	N/A
	8	128	-Always HI-	N/A
3	1	1	PWR SUP (LO on error)	N/A
(1A2A24)	2	2	COL ERR (LO on error)	TCA36/TCA1
	3	4	MON DIODE (LO on error)	TCA36/TCA1

TABLE 3-1 (Cont'd)
DATA LATCH MENU

D/L No	Bit No	Decimal	Function	Reset
	4	8	>1 COL RAD PWR (LO on error)	TCA36/TCA1
	5	16	>1 COL PERC MOD (LO on error)	TCA36/TCA1
	6	32	>1 COL GEN NULL (LO on error)	TCA36/TCA1
	7	64	-Always HI-	N/A
ļ	8	128	-Always HI-	N/A
		<u> </u>		L

### 3.7.2 STATUS TEST Operation

For a STATUS TEST, the variable E is assigned an array size of 36 x 4 and the status data is read and stored for each TCA starting at TCA1. During the operation of this routine the A and B values are continuously decoded such that the TCA count is denoted by an '†' in the display and column error data may be denoted by an 'X' under the appropriate TCA (A SYS RAD PWR error may also be indicated at each TCA). The C and D values are decoded following TCA36. This results in program time being saved with no loss in data, since all errors contained in byte 3 and 4 are reset only on the TCA36 to TCA1 transition (see Table 3-1). Following a STATUS TEST, the raw data may be inspected by entering PRINT E then entering a carriage return (C/R) on the computer keyboard. The display for this operation, in the absence of a fault, would be:

1	254	255	255
2	254	255	255
3	254	255	255
36	254	255	255

The second byte is seen to be 254. This result is obtained since the 1 bit on this latch is the output of the ERROR BUS where a TTL LO indicates no errors (see Table 3-1). This byte = 254 at TCA36 is decoded by the computer as "OPERATION NORMAL".

### 3.7.3 EXECUTIVE Interrupt Operation

The second secon

When in the EXECUTIVE mode an antenna error results in an interrupt at TCA36. In this instance the variable E is assigned an array size of  $1 \times 4$  and only that data currently on the data latches is read. In the ever+ that a column error has occurred, the TCA data latch will contain a number 1 less than the TCA at which the first error occurred. Specific column error data

is not present (the column error latches going to data latch 1 are reset following each change in TCA). All other errors will still be present in bytes 3 and 4 since latches 2 and 3 are reset only by the transition from TCA36 to TCA1 and an interrupt disables this transition.

The fact that a column error (GEN NULL, COL PERC MOD or COL RAD PWR) has occurred is indicated by the SOFTFAIL - COL ERROR bit on data latch 3. Similarly a COL MON DIODE failure would be retained and displayed. If more than one column error has occurred the appropriate >1 COL error will be denoted (the + still indicates the TCA of the first column where an error was detected). Complete failure data can be attained by performing the STATUS TEST routine. If the error is not column related the +1 computer function will result in TCA37 which places the + under NC (non-column), and the appropriate error is indicated by an 'X' on the display.

## 3.8 Software

A complete listing of all program software is shown in Figures 3-4 through 3-6.

```
---hANTEC---
4 %bilE 637,97:
5 INIT
€ GG TG 100
E INIT
9 GO TO 500
12 FAGE
13 h=3
14 *EYTE 637,101:
15 GO TO 135
16 FAGE
17 WEYTE 637,59:
18 GO TO 1575
20 GO TO 4300
100 FAGE
105 PRINT "EXECUTIVE. SRC ENAPLED"
11C PHINT "J-TO HUN TESTS. U/D KFY:"
115 GUSUB 220
120 INIT
125 n=1
130 WEYTE @37,100:
135 WHYTE 637.96:
145 SET KEY
147 IF h=3 ThEN 3CO
150 ON SEC THEN 170
1EO WAIT
165 GO TO 160
170 rOLL F.G:5.1
160 GO TO F OF 300
190 END
200 FRINT "J-TO CONTINUE, U/D REY:"
210 PRINT " "1" EXECUTIVE"
220 PHINT " '2' STATUS TEST"
230 PRINT " '3'BITE TEST"
240 FRINT " '4' DME ONLY"
250 heTuhn
300 PAGE
320 GOSUB 1000
330 DELETE N.E
340 N=1
350 WEYTE @16.25:
360 WBYTE 669,97:
370 GOSUE 1500
350 GUSUB 2500
390 IF H=3 THEN 430
400 NEYTE 637,97:
410 WBYTE 663,95:
420 GO TO 615
430 PRINT "ALL'X' EXC PWR SUP, SYS HAD PWR"
440 FRINT "DEPRESS U/D KEY'1" TO FFSET"
450 WAIT
```

Figure 3-4. Main Program (FIND 1)

```
5CO FAGE
510 GOSUB 1000
520 DELETE N.E
522 N=36
524 FOR K=1 TO 1400
SEE NEXT K
540 WEYTE GES.SE:
560 GOSUB 1500
570 IF E(36,2)<>254 THEN 610
560 MOVE C.30
590 PRINT "OPERATION NORMAL"
€00 G0 T0 €20
610 GOSUB 25CO
615 FRINT "SRC DISABLED"
€20 GOSUE 200
630 PhINT " '5'PHINT DATA"
635 WEY1E 663,95:
640 ENL
1000 MOVE 0.92.5
1C10 PRINT "I----TACAN ANTENNA STATUS----"
1020 FRINT "J-COL ERRCK5---I-C00000000111111111122222222223333333"
1030 FilhT "I-123456789012345678901234567890123456C"
1040 PHINT "TEST COL ADDR"
1050 PAINT "MON DIGEE"
10EU PRINT "GEN NULL"
1070 PHINT "HAD PWR"
1080 PHINT "PERCENT MOD"
1090 Phini "J-Hand Eddors---I-I-SOFT EPHORS---"
1100 PHINT - ->1 GEN NULLI-I- -SYS CLK-
1110 Phint " ->1 RAD PWhi-i- -hef CLK"
1120 PRINT " ->1 FERCENT MODI-I- -TONE"
113C PRINT " -CLK FRECI-I- -MON DIODE"
1140 Phint " -Nok Thigi-i- -COL ERROR"
1150 PHINT " -AUX TRIGI-I- -FWR SUP"
1160 PHINT . "I-I- -SYS RAD FWR"
1170 HOVE 24,61.5
1180 DRAW 97,81.5
1190 MOVE 24.78.4
1200 DhAW 97,78.4
1210 MOVE 24.75.5
1220 DRAW 97,75.5
1230 MOVE 24.72.7
1240 DkAh 97.72.7
1250 MOVE 24,69.9
1260 DAAW 97.69-9
1265 MOVE 0.25
1270 hEluhn
```

Figure 3-4. Main Program (FIND 1) - Cont'd

```
1500 LIM E(N.4)
1510 FOR I=1 TO N
1526 hEYTE E(1.1), E(1.2), E(1.3), E(1.4)
1530 A=AES(E(I.1))
1535 IF A>126 THEN 1575
1540 IF A>64 THEN 1565
1545 IF N=36 THEN 1630
1550 A=A+1
1555 GO TO 1€30
1575 PHINT "DME GNLY"
1580 GO TO 1590
1565 PHINT "BITE CLK ERR"
1590 affil 663.95:
1592 N=1
1595 FRINT "DEFRESS UND KEY'1" TO RESET"
1600 ENL
1630 B=ABS(E(I.2))
1640 C=ABS(E(I,3))
1650 E=AbS(E(I,4))
1660 F=30-5+A+1-792
1670 MOVE P.81-9
1680 PHINT ""
1690 GOSUE 2000
1700 NEXT I
1720 KETUKN
2000 IF B=255 Then 2290
2010 B=B-224
2020 IF B=>0 THEN 2070
2030 MOVE P.75-6
2040 PRINT "X"
20E0 B=B+32
2070 B=B-16
2080 IF B=>0 THEN 2130
2090 MOVE P.70
2100 PHINT "X"
2120 B=B+16
2130 b=B-8
2140 IF E=>0 THEN 2190
2150 MOVE F.72-8
2160 PhINT "X"
2160 E=6+6
2190 b=b-4
22CO IF B=>C THEN 225C
2210 MOVE 0.44-7
2220 PhINT "I-I-X"
2240 B=b+4
2250 B=E-2
2260 IF B=>0 THEN 2290
2270 MCVE 1.78.5
2280 PHINT "X"
2290 RETURN
```

Figure 3-4. Main Program (FIND 1) - Cont'd

2500 IF C=255 ThEN 2850 2510 C=C-224 2520 IF C=>C THEN 2570 2530 MOVE 0.61.5 2540 PHINT "1-1-X" 2560 C=C+32 2570 C=C-16 2560 IF C=>0 THEN 2630 2590 MOVE 0.55-9 2600 PHINT "I-I-X" 2620 C=C+16 2630 C=C-6 2640 IF C=>0 THEN 2690 2650 MOVE C.47.4 ZEEO PHINT "X" 2660 C=C+6 2690 C=C-4 27CC IF C=>0 THEN 2750 2710 MOVE C.50.3 272C PRINT "X" 2740 C=C+4 2750 C=C-2 276C IF C=>O THEN 2810 2770 MOVE 0,53-1 2760 PRINT "X" 2860 C=C+2 2610 C=C-1 2826 II C=0 THEN 2650 2830 MOVE 0,58.7 2540 PhINT "I-I-X" 2650 IF D=255 THEN 320C 2860 D=D-224 2670 IF D=>0 THEM 2920 2660 MOVE 0.61-5 2890 PHINT "X" 2910 D=D+32 2920 D=U-16 2930 IF D=>0 THEN 2960 2940 MOVE 0.55-9 2950 PHINT "X" 2970 D=D+16 2980 D=D-8 2990 IF D=>0 THEN 3040

Figure 3-4. Main Program (FIND 1) - Cont'd

```
3000 FOVE 0.58.7
3010 rhIN1 "X"
3030 D=D+6
3040 D=D-4
3050 IF b=>0 Then 3100
3060 MOVE 0.53-1
307C FRINT "I-I-A"
3090 D=L+4
3100 b=b-2
3110 IF L=>0 THEN 3160
3120 MOVE 0.5C-3
3130 Phint "I-I-X"
3150 D=D+2
316C D=D-1
3170 IF D=>0 THEN 3200
3180 MOVE 0.47.4
3190 PRINT "I-I-X"
3200 MOVE 0.30
3210 hETUKN
4300 FIND 3
4310 WHITE N
4320 FOR I=1 TO N
4330 WRITE E(1,1), E(1,2), E(1,3), E(1,4)
4340 NEAT I
4350 FIND 2
4360 OLD
```

Figure 3-4. Main Program (FIND 1) - Cont'd

```
4 GOSUB 100
5 FIND 1
e old
7 ENL
100 FINL 2
105 head 653: N
110 DIM E(N.4)
120 FOR I=1 TO N
130 hEAD @33:E(I.1).E(I.2).E(I.3).E(I.4)
14C NEXT I
150 PhINI @41,15:150
160 FRINT 637.26:1 .
170 Phint 641:"J----TACAN ANTENNA STATUS---"
180 FOR J=1 TO N
190 IF E(J,1)<37 THEN 220
195 IF E(J.1)>126 THEN 690
200 PHIN1 641: "PITE CLOCK FAILUFF"
210 GO TO EEG
220 NEXT J
230 IF E(N.2) <> 254 THEN 260
240 PRINT @41: "OPERATION NORMAL"
250 GO TO 660
260 FRINT 641:"J --- COLUMN ERHORS"
270 FAINT @41: USING 290:"TCA"."GEN"."KAD"."PEFC"."YON"
260 Phin7 641: USING 290: "."NULL". "Phin". "MOD". "FIODE"
290 IMAGE 5(EA)
300 FOR I=1 TO N
305 IF N=1 THEN 320
307 IF I=3€ THEN 320
310 IF E(I.2)>253 THEN 360
320 F=E(I,2)-224
330 GOSUB 10CC
340 PRINT 641: USING 350:E(I.1).As.Cs.Ps.Ds
350 IMAGE 2D.10T.4(8A)
360 NEXT I
370 GOSUE 2000
360 PRINT @41:"J----HARD ERHORS"
39G IF C1=0 THEN 410
400 FRINT 641:">1 COL GEN NULL"
410 IF C3=0 THEN 430
420 PRINT @41:">1 COL RAD PWR"
```

Figure 3-5. Print Program (FIND 2)

```
1230 F=F-2
1240 IF I=>0 THEN 1280
1250 D$="X"
1260 F=F+2
1270 GO TO 1290
1280 D$=" "
1290 F=F-1
1300 IF h=>0 THEN 1330
1310 AC=1
1320 GO TO 1340
1330 AE=0
1340 hETUKN
2000 F=E(N.3)-224
2010 IF F=>0 1hEN 2060
2030 E1=1
2040 F=F+32
2050 GO TO 2070
2060 B1=0
2070 F=F-16
2060 IF F=>0 Then 2120
2090 B2=1
2100 I=F+16
2110 GO TO 2130
2120 B2=0
2130 F=F-8
2140 IF F=>0 THEN 2160
2150 F3=1
2160 F=F+8
2170 GO TO 2190
2180 B3=0
2190 F=F-4
2200 IF F=>0 THEN 2240
2210 E4=1
2220 F=F+4
2230 GO TO 2250
2240 B4=0
2250 F=F-2
2260 IF F=>0 THEN 2300
2270 E5=1
2280 F=F+2
2290 GO TO 2310
2300 E5=0
2310 F=F-1
2320 IF F=0 THEN 2350
2330 F6=1
2340 GO TO 2360
2350 BE=0
```

Figure 3-5. Print Program (FIND 2) - Cont'd

```
430 IF C2=0 THEN 450
44C PhINT 641:">1 COL PERC PCD"
450 IF E5=0 THER 470
460 PhINT 641:"CLK FREC"
47C IF E4=0 THEN 490
480 Phint 641:"Nok Thic"
490 II 13=0 THEN 510
500 Phint @41: "AUX Trig"
510 FRINT 641:"J----SOFT ERRORS"
520 IF b1=C THEN 540
530 FhINT 641:"SYS CLK"
540 IF BE=O THEN 5EO
550 FRINT &41: "REF CLK"
560 IF E2=0 THEN 560
570 FRINT G41: TONE"
560 IF C4=G THEN ECO
550 FRINT G41: "MON DIODE"
€00 IF C5=0 Then €20
610 PHINT 641: "COL ERROR"
EZC IF CE=O THEN E40
630 Phint 641: "Pwh SUP"
640 IF A4=0 THEN 660
650 FRINT 641: "SYS HAD FWR"
660 PRINT G41:"J----END OF DATA---"
670 PRINT 637.26:C
EBO RETURN
690 FRINT @41:"DME ONLY MODE"
700 GG TG 660
1000 IF F=>0 ThEN 1040
1010 As="X"
1020 F=F+32
1030 GO TO 1050
1040 85=" "
1050 F=F-16
1060 IF F=>0 THEN 1100
1070 B$="X"
1080 F=F+16
1096 GO TO 1110
1100 B$=" "
1110 l=1-E
1120 IF F=>0 THEN 1160
1130 Cs="X"
1140 F=F+6
1150 GO TO 1170
1160 Cs=" -
1170 F=F-4
1160 IF F=>0 THEN 1220
1190 A4=1
1200 F=i+4
1210 GO TO 1230
1220 44=0
```

The state of the s

Figure 3-5. Print Program (FIND 2) - Cont'd

```
23E0 1=E(1:4)-224
2370 IF F=>0 THEN 2410
2350 C1=1
2350 1=1+32
2400 GG TG 2420
2410 C1=0
2420 b=1-16
2430 IF F=>0 THEN 2470
2440 C2=1
2450 F=F+1E
2460 GO TO 2460
2470 C2=0
2460 F=1-8
2490 IF F=>0 THEN 2530
2500 C3=1
2510 F=F+6
2520 GO TO 2540
2530 C3=0
2540 F=F-4
2550 IF F=>0 THEN 2590
2560 C4=1
2570 F=i+4
2580 GO TO 2600
2590 C4=0
26CO F=F-2
2610 IF F=>0 THEN 2650
2620 C5=1
2630 F=F+2
2640 GO TO 2660
2650 C5=0
2660 F=F-1
2670 IF 1=>0 THEN 2700
2680 CE=1
2690 GO TO 2710
2700 CE=0
2710 RETURN
```

Figure 3-5. Print Program (FIND 2) - Cont'd

```
---RANTEC---
4 INIT
5 FAGE
6 SET KEY
7 GO TO 100
8 CO TO 500
12 GO TO 700
16 RESTORE 3490
17 GO TO 300
20 RESTORE 3480
22 GG TO 300
24 PAGE
25 FRINT "DME ONLY, SRC DISAPLED"
26 PRINT "DEPRESS U/D KEY'1' TO RESET"
27 END
26 RESTORE 3470
29 GO TO 300
100 FRINT "EXECUTIVE. SRC ENABLED"
110 Phint "J-TO RUN TESTS. U/D KEY:"
120 GOSUE 240
130 ON SK4 THEN 160
140 WAIT
150 GO TO 140
160 POLL E.F:5.1
170 GO TO E OF 300
180 RETURN
190 END
200 PHINT "J-TO CONTINUE. U/D KEY:"
210 PRINT " '1' EXECUTIVE"
240 PRINT " '2'STATUS TEST-NOMAL OPR"
260 PRINT " '3'BITE TEST"
270 PRINT " '4'SIMULATED COLUMN FAULT"
280 PHINT " '5' SIMULATED BITE CLK FAULT"
285 PRINT " 'E'SIMULATED DME ONLY"
287 PHINT " '7' SIMULATED NON-COLUMN FAULT"
290 RETURN
300 FAGE
320 GOSUB 1000
330 DELETE N.E
340 N=1
370 GUSUB 1500
380 GOSUB 2500
390 PHINT "SRC DISABLED"
400 GUSUE 200
410 END
```

Figure 3-6. Demonstration Program (FIND 4)

```
500 PAGE
510 GOSUE 1000
520 DELETE N.E
530 N=36
540 kesture 3510
550 FOR J=1 TO 1000
555 NEXT J
560 GOSUB 1500
570 GOSUB 2500
560 GOSUB 1600
590 GUSUB 200
EOU END
700 PAGE
720 GOSUB 1000
730 DELETE N.E
740 N=1
750 RESTORE 3500
770 GOSUB 1500
780 GUSUB 2500
790 FRINT "ALL'X" EXC PWR SUP.SYS RAD PWR"
800 FRINT "DEFRESS U/D KEY'1' TO RESET"
810 END
1000 MOVE 0,92.5
1010 PHINT "I -----TACAN ANTENNA STATUS----"
1020 PAINT "J-COL ERRORS---I-000000000111111111122222222222333333N"
1030 FRINT "I-123456789012345678901234567890123456C"
1040 FRINT "TEST COL ADDR"
1050 PRINT "MON DIODE"
1060 PRINT "GEN NULL"
1070 PHINT "RAD PWR"
1080 PRINT "PERCENT MOD"
1090 PRINT "J-HARD ERRORS---I-I-SOFT ERRORS---"
1100 PRINT " ->1 GEN NULLI-I- -SYS CLK"
1110 PRINT " ->1 BAD PWRI-I- -REF CLK"
1120 PRINT " ->1 PERCENT MODI-I- -TONE"
1130 PRINT " -CLK FRECI-I- -MON DIODE"
1140 FRINT " -NOR TRIGI-I- -COL ERROR"
1150 PHINT " -AUX TRIGI-I- -PWR SUP"
1160 PHINT "I-I- -SYS RAD PHR"
1170 MOVE 24,81.5
1180 DRAW 97,61.5
1190 MOVE 24.78.4
1200 DRAW 97,78-4
1210 MOVE 24,75.5
1220 DRAW 97,75.5
1230 MOVE 24,72.7
1240 DHAW 97,72.7
1250 MOVE 24,69.9
1260 DRAW 97,69.9
1270 KETUKN
```

Figure 3-6. Demonstration Program (FIND 4) - Cont'd

```
1500 FOR I=1 TO N
1520 READ A.E.C.D
1540 IF A<36 THEN 1660
1550 MOVE 0.30
1560 PRINT "BITE CLK ERR"
1570 PHINT "DEPRESS U/D KEY'1' TO RESET"
1580 END
1660 P=30.5+A+1.792
1670 MOVE P.81-9
1660 FRIET ":"
1690 GOSUE 2000
1692 FOR J=1 TO 200
1694 NEXT J
1700 NEXT I
1720 HETURN
1800 HOVE 0.40
1610 IF P<>0 THEN 1830
1620 PRINT "OPERATION NORMAL"
1025 FRINT "SHG DISABLED"
1830 RETURN
2000 IF B=127 THEN 2290
2010 B=B-96
2020 IF B=>0 THEN 2070
2030 MOVE P.75.6
2040 PHINT "X"
2050 IF B=-1 THEN 2290
2060 B=B+32
2070 B=B-16
2080 IF E=>O THEN 2130
2090 MOVE P.70
2100 PHINT "X"
2110 IF B=-1 THEN 2290
2120 B=B+16
2130 B=E-6
2140 IF E=>0 THEN 2190
2150 MOVE P.72-8
2160 PRINT "X"
2170 IF B=-1 THEN 2290
2180 B=B+8
2190 E=B-4
2200 IF b=>0 ThEN 2250
2210 MOVE 0.44.7
2220 FRINT "I-I-X"
2230 IF B=-1 THEN 2290
2240 B=E+4
2250 B=B-2
2260 IF B=>0 THEN 2290
2270 MOVE F.78.5
2260 PHINT "X"
2290 RETURN
```

Figure 3-6. Demonstration Program (FIND 4) - Cont'd

```
2500 IF C=127 THEN 2850
2510 C=C-9€
2520 IF C=>O THEN 257C
2530 HOVE 0,61.5
2540 PRINT "I-I-X"
2550 IF C=-1 THEN 2850
2560 C=C+32
2570 C=C-16
2560 IF C=>0 THEN 2630
2590 MOVE 0,55.9
26CO FRINT "I-I-X"
2610 IF C=-1 THEN 2850
2620 C=C+16
2630 C=C-6
2640 IF C=>0 THEN 2690
2650 HOVE 0.47.4
2660 PHINT "X"
2670 IF C=-1 THEN 2850
2680 C=C+8
2690 C=C-4
2700 IF C=>O THEN 2750
2710 MOVE 0.50.3
2720 PRINT "X"
273C IF C=-1 THEN 2850
2740 C=C+4
2750 C=C-2
2760 IF C=>0 ThEN 2810
2770 MOVE 0,53-1
2780 FRINT "X"
2790 IF C=-1 THEN 2850
2800 C=C+2
2810 C=C-1
2820 IF C=0 THEN 2850
2830 MOVE 0.58.7
2840 PHINT "I-I-X"
2850 IF D=127 THEN 3200
2860 D=D-96
2670 IF D=>0 THEN 2920
2860 MOVE 0.61.5
2890 PHINT "X"
2900 IF b=-1 THEN 3200
2910 D=D+32
2920 D=D-16
2930 IF D=>0 THEN 2980
2940 MOVE 0.55.9
2950 PRINT "X"
2960 IF D=-1 THEN 3200
2970 D=D+16
2960 D=D-6
```

Figure 3-6. Demonstration Program (FIND 4) - Cont'd

```
2990 IF D=>C THEN 3040
3000 MOVE 0.58.7
3010 PHINT "X"
3020 IF D=-1 THEN 3200
3030 D=D+6
3040 D=D-4
3050 IF D=>0 THEN 3100
3060 MOVE 0.53-1
3070 FAINT "I-I-X"
3080 IF D=-1 THEN 3200
3090 D=D+4
3100 D=D-2
3110 IF D=>C THEN 3160
3120 MOVE 0,50-3
3130 PHINT "I-I-X"
3140 IF D=-1 THEN 3200
3150 D=D+2
3160 D=D-1
3170 IF D=>0 THEN 3200
3180 NOVE 0,47.4
3190 PHINT "I-I-X"
3200 MOVE 0.30
3210 RETURN
3470 DATA 37,127,127,126
3480 DATA 65,127,127,127
3490 DATA 5,127,127,117
3500 DATA 5,68,0,65
3510 DATA 1,127,127,127,2,127,127,127,3,127,127,127,4,127,127,127
3520 DATA 5,127,127,127,6,127,127,127,727,127,127,127,8,127,127,127
3530 DATA 9,127,127,127,10,127,127,127,11,127,127,127,127,127,127
3540 DATA 13,127,127,127,14,127,127,127,15,127,127,127,16,127,127,127
3550 DATA 17.127.127.127.18.127.127.127.19.127.127.127.127.127.20.127.127.127
3560 DATA 21,127,127,127,22,127,127,127,23,127,127,127,24,127,127,127
3570 DATA 25,127,127,127,26,127,127,127,27,127,127,127,26,127,127,127
3560 DATA 29,127,127,127,30,127,127,127,31,127,127,127,32,127,127,127
3590 DATA 33,127,127,127,34,127,127,127,35,127,127,127,36,176,127,127
```

Figure 3-6. Demonstration Program (FIND 4) - Cont'd

### 4.0 ANTENNA GROUP TESTS AND INSTALLATION

# 4.1 <u>Acceptance Tests</u>

Following completion of all modification, the antenna group was subjected to a complete acceptance test. This test was in accordance with Rantec documents 11002-ATP and 11016-ETP. The test report was furnished to the FAA as a part of Progress Report 4 (Rantec No. 11016 PR4).

# 4.2 Installation

The antenna was delivered to the FAA test center at Atlantic City and following the arrival of Rantec personnel, was installed at a VORTAC test facility. The antenna was installed on top of the existing VOR cone (see paragraph 6.d).

The modulation generator interconnecting cables and rf cable were routed through the VOR cone down into the equipment room. The modulation generator and test set were installed at a temporary location within the equipment room.

All equipment was then interconnected and the complete TACAN system was turned on. It was discovered that noise was causing a problem with the monitor-diode BITE circuit. The low pass filter on PCC1A2A22 used with the monitor-diode bias-level detector was modified to decrease its knee frequency. This cured the problem and will not effect the failure-detection capability of that BITE circuit.

Since no external monitor equipment or flight-check aircraft were available, no system test could be performed.

It was noted that the antenna monitor circuitry indicated an occasional antenna fault; however, the fault never persisted long enough to obtain column-related data on the test set. It was believed that the problem was associated with the monitor circuit and not the actual radiated signal. An attempt was made to fix the prob  $\epsilon m$  by reseting the low-percent modulation level comparator. This had only marginal success.

Since this problem was not encountered at Rantec, it is believed to be the result of system noise getting into the antenna monitor lines. A second PCCA22 was fabricated at Rantec incorporating a digital circuit to eliminate monitor sensitivity to short term noise bursts. Unfortunately the PCC could not be fully checked out at Rantec and was found to be inoperative at the FAA test center. It is felt, however, that the design is solid and should be incorporated in future modulation generators.

#### 5.0 CONCLUSIONS

The modified TACAN Antenna Group has met the initial requirements of the program and now awaits test and evaluation at Atlantic City. It is believed the antenna group will meet all FAA requirements both with respect to performance and the operation of the newly designed interface.

#### 6.0 RECOMMENDATIONS

As a result of the initial operation and installation of the TACAN antenna group there are several areas which need to be dealt with in an FAA/RANTEC design review meeting.

- a. Upon initial turn-on the modulation generator comes on in the DME-ONLY mode. Initialization of full performance requires that the controller (test set) be connected and placed in its EXECUTIVE mode. It may be desirable that power-up of the system not require computer intervention. Such a change is very minor in nature.
- b. There is some doubt that the Second Generation VORTAC requires a bipolar TONE signal. If this is the case, that circuitry and its associated BITE can be removed from the modulation generator.
- c. The modulation generator meets the requirements of the IEEE-488 bus. The use of this interface with the VORTAC system will require programing of that system computer. The programing now accomplished in the test set should prove useful as a guide for that purpose; however, an interface between Rantec and the beacon system programmer should prove most beneficial.
- d. The antenna connectors are presently located on the side of the antenna. For installation on the VOR cone, it would be desirable that these connections be made on the bottom of the antenna. At Atlantic City a hole was made through the adapter ring to accomplish the required cabling. It is desirable, of course, that the solution to this problem be made in a way which does not impact the antenna seal.
- e. Some system of ordering the antenna/modulation generator interconnecting cables is required. It was noted in Atlantic City that at least three different installation configurations exist which will require different cable lengths.
- f. Incorporate a noise immunity circuit in the antenna monitor electronics (see paragraph 4.2).

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- f. Incorporate a noise immunity circuit in the antenna monitor electronics (see paragraph 4.2).

# 7.0 REFERENCE DOCUMENTS

The following documents are referenced here as applicable to this project:

Statement of Work - Department of Transportation (DOT)
Contract No. DTF01-80-C-10148

Technical Manual - 0E-258/URN TACAN Antenna Group Rantec Document No. 11002-TM-C

Technical Manual Addendum

Rantec Document No. 11016-TMA

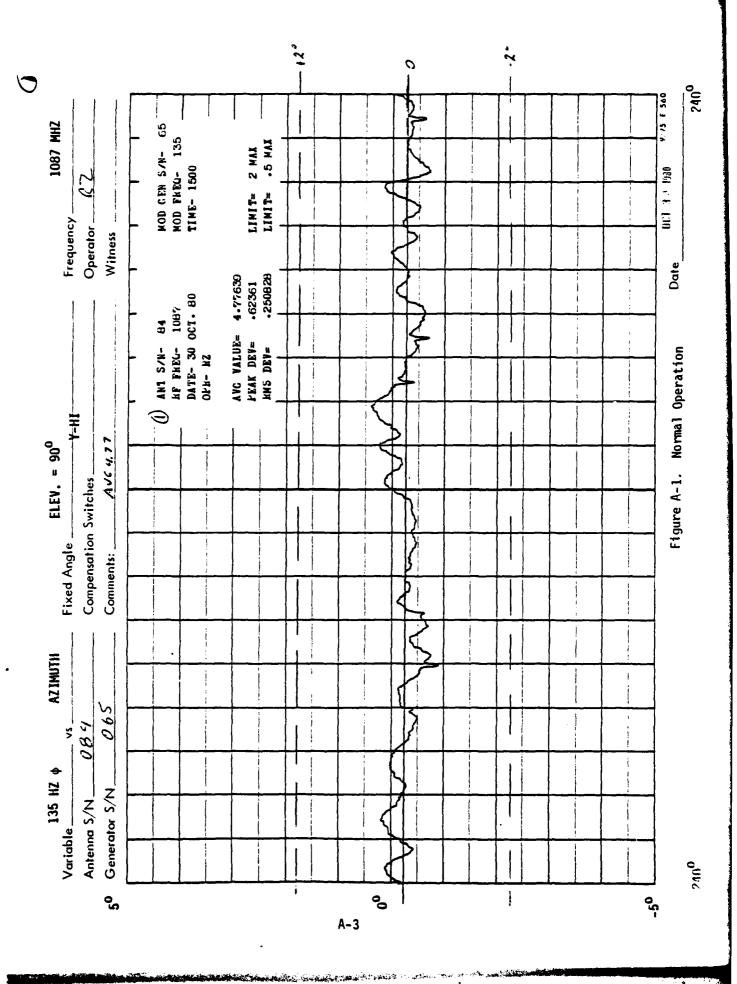
#### APPENDIX A

### ANTENNA FAULT TESTS

In an effort to gain further insight into antenna group performance as a function of various faults, a series of patterns were obtained for the 135 Hz phase-track (bearing) error, using various faults. These tests were performed in Rantec's 120-foot anechoic chamber using the specialized test equipment designed for TACAN antenna acceptance tests. Patterns are shown in Figures A-1 through A-12. The following description deals with these patterns:

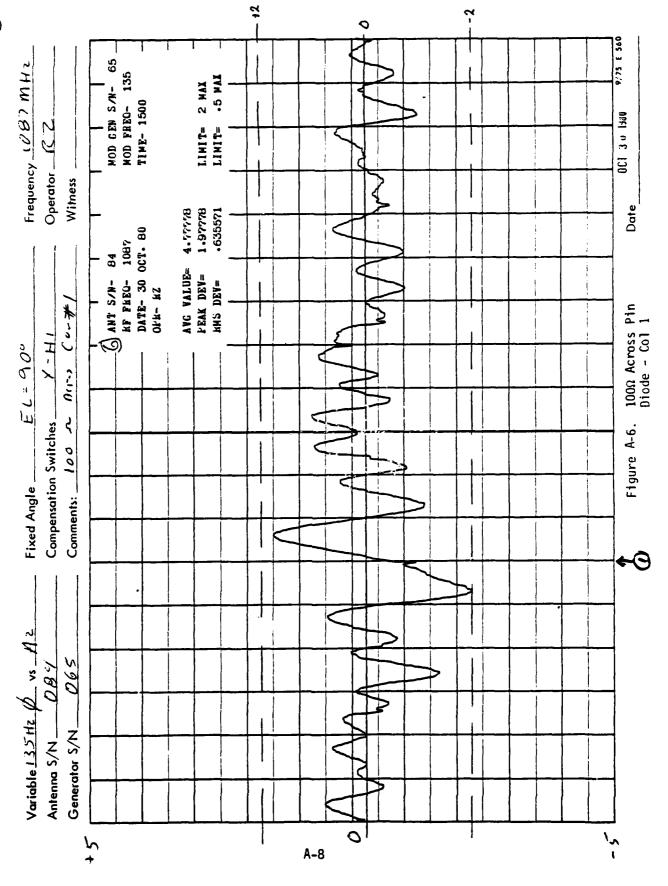
- A-1 Normal pattern.
- A-2 Gain of drive amplifier changed slightly no significant pattern change.
- A-3 Short output of drive amplifier  $\pm 2^{0}$  peak error on either side of faulty drive.
- A-4 Short PIN diode modulator  $\pm 2^0$  peak error on either side of shorted modulator.
- A-5 1K resistor across PIN diode modulator (test of PIN diode leakage) no significant change.
- A-6  $100\Omega$  resistor across PIN diode modulator (increased leakage)  $\pm 2^0$  peak error on either side of affected modulator.
- A-7 PIN diode removed (open)  $\pm 2^{\circ}$  error on either side of affected drive.
- A-8 RF cable removed (no carrier)  $\pm 2^{\circ}$  error on either side of affected column.
- A-9 Adjacent PIN diode shorted (two column error) ±2.5° error on either side of adjacent column.

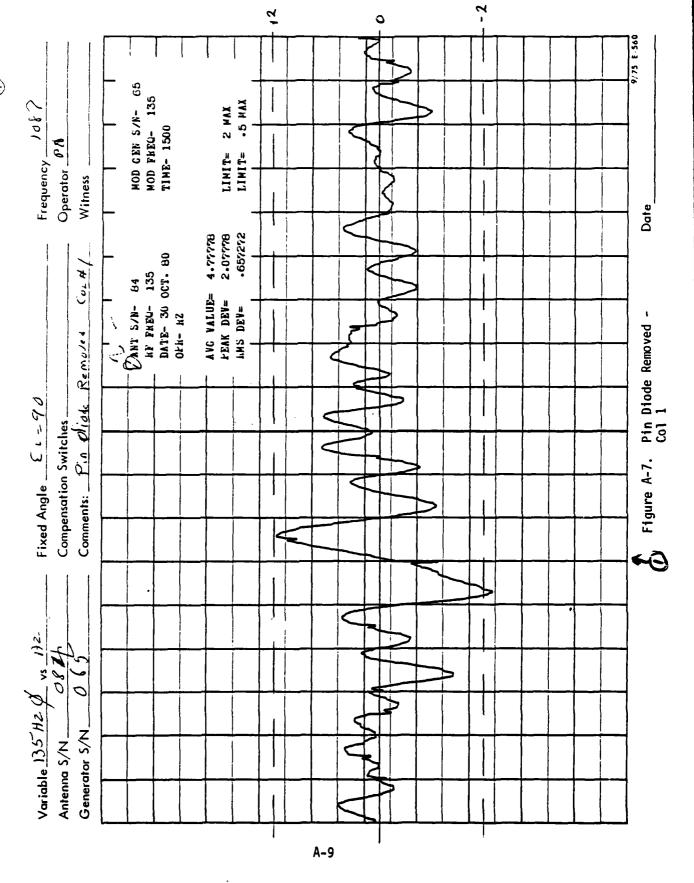
- A-10 PIN diodes shorted, two columns  $30^{\circ}$  apart (two column error)  $\pm 2.2^{\circ}$  error over broader section.
- A-11 PIN diodes shorted, two columns  $80^{\circ}$  apart  $\pm 1.8^{\circ}$  errors at both columns.
- A-12 PIN diodes shorted, two columns  $180^{\circ}$  apart (both outputs of one push-pull modulator)  $\pm 2.2^{\circ}$  error with roughness throughout pattern.

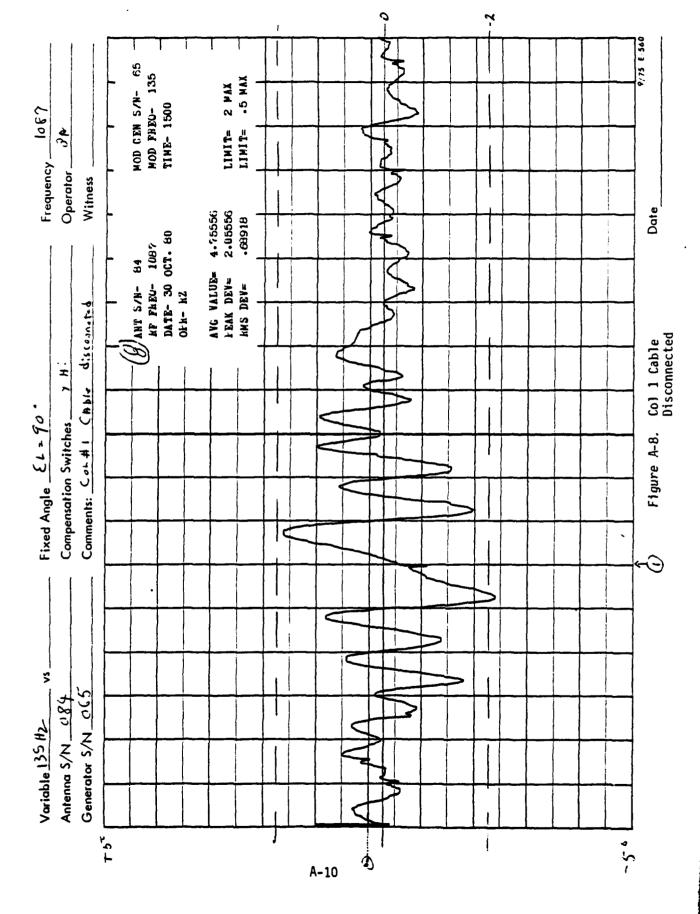


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